

Also referred to as:



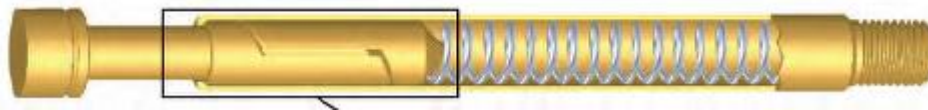
- ✓ Pogo Pin
- ✓ Contact pin
- ✓ Bed of nails
- ✓ Fixture pin
- ✓ ATE Pins

What is a Spring Contact Test Probe?

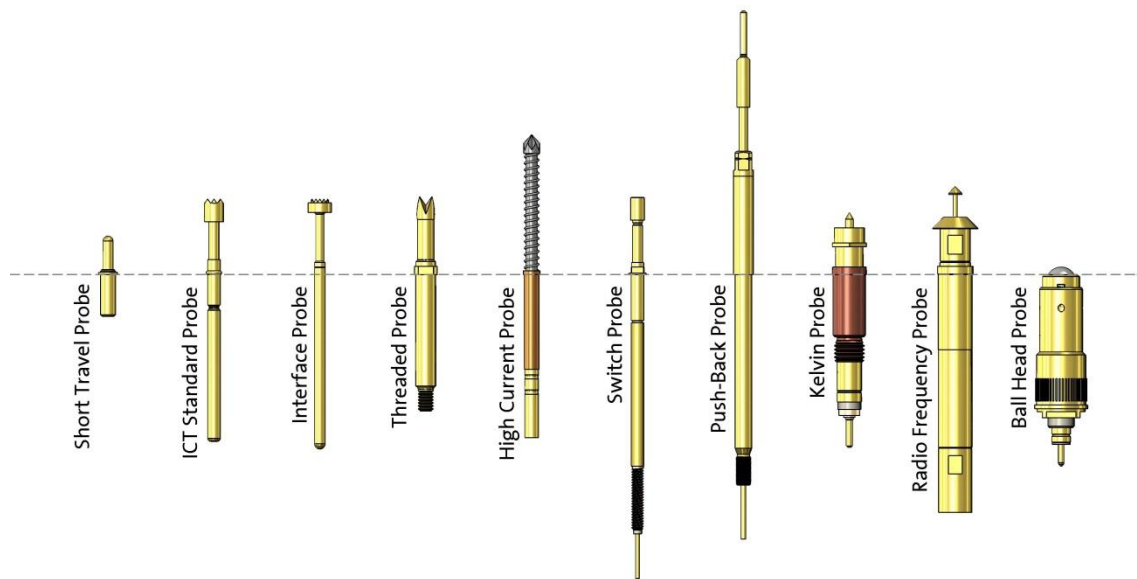
Spring Contact Test Probes are used to make contact to various test points on printed circuit boards (PCB's), components and wiring fields. When employed in special test modules, the probes can be used to test connector-cable systems. The test probes can also be used in control engineering units or as a charging contact.

Spring Contact Test Probes are made up of a tubular barrel, a spring and a plunger. Plunger tip styles can be provided in a variety of tip styles and different spring pressures. This ensures the best contact with the test surface.

Probes can also be mounted into receptacles (housing units) where an electrical connection is made. This also allows the test probes to be easily removed for repair or replacement.



Contact Probes are available for various applications. Below is a brief overview.



Threaded Probes

Threaded for a secure fit. Used in modules for the test of wire harnessing.

High Current Probes

Used for high current applications. Designed for a very small probe resistance.

Switch Probes

Special probes with integrated switch element, mainly used for presence.

Push Back Probes

During the push back of connectors, the tight seat of the connector elements are verified.

Kelvin Probes

Very low resistances of components are measured by the "Kelvin 4-wire measurement"

Radio Frequency Probes

Special Coaxial contact probes are used to transmit the high frequency signals. The coaxial probes have an inner conductor for the transmission of the signal and an outer conductor for shielding.

To view our full range of Test Probes, please click [here](#)